

Art Unit: 2829

09/740,634

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09/17/04

1 (currently amended). An integrated circuit component, comprising:

a plurality of circuit points not being ~~not~~ directly externally accessible, providing a reference signal provided by the integrated circuit component for test purposes, and various electrical signals of the integrated circuit component to be monitored for test purposes;

at least one connecting contact point being externally accessible; and

a multiplexer having an output connected to said at least one connecting contact point and having a plurality of inputs, each one of said plurality of inputs being connected to a respective one of said plurality of circuit points, permitting external access to the reference signal and to the various electrical signals.

Art Unit: 2829

2 (currently amended). The integrated circuit component according to claim 1, wherein-

said at least one connecting contact point is one of a plurality of connecting contact points,

~~a reference signal is selectively applied to one of said plurality of connecting contact points and passed on via a route within the integrated circuit component to one of said plurality of circuit points that are not externally accessible; and~~

~~said electrical signals can be selectively passed on via routes within the integrated circuit component from said plurality of circuit points that are not externally accessible to said plurality of connecting contact points other than said one of said plurality of connecting contact points.~~

3 (previously presented). The integrated circuit component according to claim 2, wherein said plurality of connecting contact points is exactly two connecting contact points.

Art Unit: 2829

4 (currently amended). The integrated circuit component according to claim 1, wherein:

said electrical signals are internal chip signals in the integrated circuit component[[]], and said reference signal are used for monitoring the timing of said internal chip signals

~~reference signals and said electrical signals can be selectively passed on to said at least one connecting contact point.~~

5 (withdrawn). The integrated circuit according to claim 1, comprising a package and wherein:

~~said plurality of connecting contact points define a plurality of inaccessible contact points are disposed on said package,~~

~~said electrical signals at said plurality of circuit points that are not externally accessible are present at said plurality of inaccessible contact points,~~

~~said electrical signals and reference signals are selectively passed on to said at least one connecting contact point, and~~

~~said at least one connecting contact point is formed by at least one of said plurality of inaccessible contact points.~~

Art Unit: 2829

6 (withdrawn). The integrated circuit according to claim 5,
wherein:

said package is a ball grid array package having a lower face;

said plurality of inaccessible contact points are located on
said lower face of said package and are thus concealed between
said package and a system board on which said package is
fitted; and

said at least one connecting contact point is electrically
conductively connected to a corresponding number of metallic
test points on the system board.

7 (previously presented). The integrated circuit component
according to claim 3, further comprising a second multiplexing
circuit.

8 (withdrawn). The integrated circuit according to claim 1,
wherein:

said multiplexing circuit is time-controlled and is provided
in the integrated circuit component surrounded by a ball grid
array package.

9 (previously presented). The integrated circuit component according to claim 7, wherein said multiplexing circuit is programmably controlled to predetermine selective passing on of the electrical signals to said at least one connecting contact point.

10 (previously presented). The integrated circuit component according to claim 1, wherein said at least one connecting contact point can be selectively used in an opposite operating direction for inputting signals to said plurality of circuit points that are not externally accessible.

11 (previously presented). The integrated circuit according to claim 1, wherein said at least one connecting contact point is connected to a component tester for analyzing the electrical signals.

12 (previously presented). The integrated circuit component according to claim 1, wherein said at least one connecting contact point is connected to a system analyzer and an application of said system analyzer analyzes the electrical signals of, at least some of said plurality of circuit points.

CLAIMS 13 THROUGH 16 ARE CANCELLED

Art Unit: 2829

17 (currently amended). An integrated circuit component, comprising:

a first plurality of circuit points of the integrated circuit component not being directly externally accessible, providing a reference signal provided by the integrated circuit component for test purposes;

a second plurality of circuit points of the integrated circuit not being directly externally accessible, providing electrical signals of the integrated circuit component to be monitored for test purposes;

a first connecting contact point being externally accessible;

a second connecting contact point being externally accessible;

a first multiplexer having an output connected to said first connecting contact point and having a plurality of inputs, each one of said plurality of inputs being connected to a respective one of said first plurality of circuit points, permitting external access to the reference signal; and

a second multiplexer having an output connected to said second connecting contact point and having a plurality of inputs, each one of said plurality of inputs being connected to a respective one of said second plurality of circuit points, permitting external access to the various electrical signals.

CLAIM 18 CANCELLED